

**Search Notes**

Application/Control No.

10/691,172

Examiner

Paul D. Kim

Applicant(s)/Patent under  
Reexamination

YAO ET AL.

Art Unit

3729

**SEARCHED**

Class	Subclass	Date	Examiner
29	603.03- 603.06 603.07	4/7/2006 ↓	PK
360	294.4-		
	294.7		
216	39,65	4/10/2006 ↓	PK
205	119 122		
427	127 128		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Text Search EAST/NPL (IEEE)	4/10/2006	PK